

January 5, 2004

To: Commissioner for Patents  
P.O. Box 1450  
Alexandria, VA 22313-1450

Fr: George O. Saile, Reg. No. 19,572  
28 Davis Avenue  
Poughkeepsie, N.Y. 12603

Subject:

Serial No. 10/686,794 10/16/03

Chia-Ta Hsieh

A FLASH EEPROM WITH FUNCTION  
BIT BY BIT ERASING

INFORMATION DISCLOSURE STATEMENT

Enclosed is Form PTO-1449, Information Disclosure Citation  
In An Application.


The following Patents and/or Publications are submitted to  
comply with the duty of disclosure under CFR 1.97-1.99 and  
37 CFR 1.56. Copies of each document is included herewith.

CERTIFICATE OF MAILING

I hereby certify that this correspondence is being  
deposited with the United States Postal Service as first class  
mail in an envelope addressed to: Commissioner for Patents,  
P.O. Box 1450, Alexandria, VA 22313-1450, on January 13, 2004.

Stephen B. Ackerman, Reg.# 37761

Signature/Date

 1/13/04

In the article, "A Dual-bit Split-Gate EEPROM (DSG) Cell in Contactless Array for Single-Vcc High Density Flash Memories," by Yale Ma et al., IEDM 94-57, pp. 3.5.1 to 3.5.4, a new source-side injection Dual-bit Split-Gate (DSG) flash EEPROM cell is designed and characterized.

The following two U.S. Patents disclose a triple polysilicon flash EEPROM array having a separate erase gate for each row of floating gates, and methods of manufacturing such an array:

- 1) U.S. Patent 5,712,179 to Yuan, "Method of Making Triple Polysilicon Flash EEPROM Arrays Having a Separate Erase Gate for Each Row of Floating Gates."
- 2) U.S. Patent 6,028,336 to Yuan, "Triple Polysilicon Flash EEPROM Arrays Having a Separate Erase Gate for Each Row of Floating Gates, and Methods of Manufacturing Such Arrays."

U.S. Patent 5,677,872 to Samachisa et al., "Low Voltage Erase of a Flash EEPROM System Having a Common Erase Electrode for Two Individual Erasable Sectors," discusses low voltage erase of a flash EEPROM system having a common erase electrode for two individual erasable sectors.

TSMC-01-280B

U.S. Patent 5,278,439 to Ma et al., "Self-Aligned Dual-Bit Split Gate (DSG) Flash EEPROM Cell," discloses a DSG EEPROM.

U.S. Patent 6,222,762 to Guterman et al., "Multi-State Memory," discloses a multi-state cell and erase method.

U.S. Patent 6,151,248 to Harari et al., "Dual Floating Gate EEPROM Cell Array with Steering Gates Shared by Adjacent Cells," discloses a EEPROM cell with gates shared by adjacent cells.

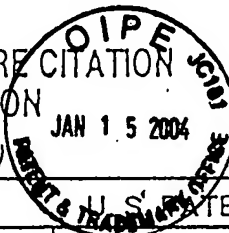
Sincerely,

A handwritten signature in black ink, appearing to be 'S. Ackerman', with a stylized flourish extending to the right.

Stephen B. Ackerman,  
Reg. No. 37761

# INFORMATION DISCLOSURE CITATION IN AN APPLICATION

(Use several sheets if necessary)



Docket Number (Optional)

TSMC-01-280B

Application Number

10/686,794

Applicant

Chia-Ta Hsieh

Filing Date

10/16/03

Group Art Unit

## U.S. PATENT DOCUMENTS

EXAMINER INITIAL	DOCUMENT NUMBER	DATE	NAME	CLASS	SUBCLASS	NUMO DATE APPROPRIATE
	5712179	1/27/98	Yuan	437	43	10/31/95
	6028336	2/22/00	Yuan	257	315	8/7/97
	5677872	10/14/97	Samachisa et al.	365	185.14	7/8/96
	5278439	1/11/94	Ma et al.	257	319	8/29/91
	6222762	4/24/01	Guterman et al.	365	185.03	8/7/97
	6151248	11/21/00	Harari et al.	365	185.14	6/30/99

## FOREIGN PATENT DOCUMENTS

	DOCUMENT NUMBER	DATE	COUNTRY	CLASS	SUBCLASS	Translation	
						YES	NO

## OTHER DOCUMENTS (Including Author, Title, Date, Port/north Pages, Etc.)

	Y. Ma et al., "A Dual-bit Split-Gate EEPROM (DSG) Cell in Contactless Array for Single-Vcc High Density Flash Memories," IEDM 94-57, 1994 IEEE, pp. 3.5.1 to 3.5.4.

EXAMINER

DATE CONSIDERED

EXAMINER: Initial if citation considered, whether or not citation is in conformance with MPEP § 609; Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to the applicant